

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10574286	OIKAWA ET AL.
	Examiner	Art Unit
	CEDRIC CHAN	1797

SEARCHED

Class	Subclass	Date	Examiner
422	99,102,104,255,261,266,292	8/21/2010	CC
134	117,150	8/21/2010	CC
216	83,84,100,8,10	8/21/2010	CC
118	400,404,427	8/21/2010	CC

SEARCH NOTES

Search Notes	Date	Examiner
inventor name search (PALM)	2/5/2010	CC
inventor name search (EAST)	2/13/2010	CC
searched US/Foreign databases -- EAST/USPat,OCR,PGPub,EPO,JPO,Derwent	2/13/2010	CC
assignee search (EAST)	8/21/2010	CC
updated class, inventor search & updated keyword search of US/For databases (see EAST History)	8/21/2010	CC

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

/C. C./
Examiner.Art Unit 1797